

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. .... 09/827,248  
Filing Date .... April 4, 2001  
Inventor .... David R. Hembree  
Assignee .... Micron Technology, Inc.  
Group Art Unit .... 2829  
Examiner .... V. Nguyen  
Attorney's Docket No. .... MI22-1684  
Title: Methods of Processing a Workpiece, Methods of Communicating Signals With  
Respect to a Wafer, and Methods of Communicating Signals Within a Workpiece  
Processing Apparatus

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT


References -- See Attached Form PTO-1449

The attached form PTO-1449 is submitted in compliance with 37 CFR §1.56. No  
admission is made regarding whether all the submitted references are prior art.

Dated: 5/25/05

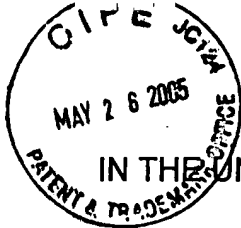
Attorney:

Respectfully submitted,

  
James D. Shaurette  
Reg. No. 39,833

EV549570253

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1684		SERIAL NO. 09/827,248	
<div style="position: relative; height: 100px;"> <div style="position: absolute; top: 0; left: 0; width: 100%; height: 100%; border: 1px solid black; border-radius: 50%; text-align: center; color: black; font-weight: bold; line-height: 1;"> CITE JOINT MAY 28 2008 PATENT &amp; TRADEMARK OFFICE </div> </div>				LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)			
				APPLICANT: David R. Hembree			
				FILING DATE April 4, 2001		GROUP 2829	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	5,703,287	12/1997	Treutler et al.			
	AB	5,945,834	8/1999	Nakata et al.			
	AC	5,478,242	12/1995	Walker et al.			
	AD	5,830,372	11/1998	Hierold			
	AE						
	AF						
	AG						
	AH						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AI						
	AJ						
	AK		EV549570253				
	AL						
EXAMINER				DATE CONSIDERED			
<p><small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small></p>							



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE


Application Serial No. .... 09/827,248  
Filing Date ..... April 4, 2001  
Inventor ..... David R. Hembree  
Assignee ..... Micron Technology, Inc.  
Group Art Unit ..... 2829  
Examiner ..... V. Nguyen  
Attorney's Docket No. .... MI22-1684  
Title: Methods of Processing Wafers and Methods of Communicating Signals With  
Respect to a Wafer

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

References -- See Attached Form PTO-1449

The attached form PTO-1449 is submitted in compliance with 37 CFR §1.56. No admission is made regarding whether all the submitted references are prior art.

Dated: 2/16/05

Respectfully submitted,  
  
James D. Shaurette  
Reg. No. 39,833

EV549568285

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1684		SERIAL NO. 09/827,248	
<div style="position: relative; height: 100px;"> <div style="position: absolute; top: 0; left: 0; width: 100%; height: 100%; border: 1px solid black; border-radius: 50%; text-align: center; line-height: 100px; font-size: 24px; font-weight: bold;">             MAY 28 2005           </div> </div>				LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)			
				APPLICANT Micron Technology, Inc.			
				FILING DATE April 4, 2001		GROUP 2858	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	6,635,852	10/21/2003	Seiwa			
	AB	6,709,878	3/23/2004	Akram et al.			
	AC	6,645,701	11/11/2003	Ota et al.			
	AD						
	AE						
	AF						
	AG						
	AH						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AI						
	AJ		FV540568285				
	AK						
	AL						
<u>EXAMINER</u>				<u>DATE CONSIDERED</u>			
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							